Cp E 432: Testing of Computing Systems

ELECTRICAL ENGINEERING

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for- manufacture, system testability and diagnosability.
3 Credits

Prerequisites

- El E 351: Models and Circuits I $target.descriptions.MinimumGrade$
- El E 385: Advanced Digital Systems $target.descriptions.MinimumGrade$
- El E 386: Advanced Digital Systems Laboratory $target.descriptions.MinimumGrade$

Instruction Type(s)

- Lecture: Lecture for Cp E 432

Subject Areas

- Computer Engineering, General

Related Areas

- Computer Hardware Engineering